

In the Specification

Please amend the Abstract of the disclosure by inserting the underlined text ("____") and removing the stricken text ("—").

V.N
12/15/04

A device testing system ~~comprising that has~~ automated test equipment (ATE), which ~~configured to~~ interfaces to a device under test (DUT). The device testing system and logic ~~configured to~~ selects a test set of data ^{including} ~~comprising~~ a plurality of test pairs, ~~the test pairs~~ indicative of DUT parameter values. The system, ~~the logic further configured to~~ selects a subset of the plurality of test pairs from the test set of data ~~and to tests~~ the DUT via the ATE with a portion of the selected subset based upon the test results of at least one of the test pairs.